

April 2001

IGBT

SGS10N60RUF

Short Circuit Rated IGBT

General Description

Fairchild's RUF series of Insulated Gate Bipolar Transistors (IGBTs) provide low conduction and switching losses as well as short circuit ruggedness. The RUF series is designed for applications such as motor control, uninterrupted power supplies (UPS) and general inverters where short circuit ruggedness is a required feature.

Features

- Short circuit rated 10us @ $T_C = 100$ °C, $V_{GE} = 15$ V
- High speed switching
- Low saturation voltage : $V_{CE(sat)} = 2.2 \text{ V} @ I_C = 10 \text{A}$
- High input impedance

Application

AC & DC Motor controls, general purpose inverters, robotics, servo controls





Absolute Maximum Ratings T_C = 25°C unless otherwise noted

Symbol	Description		SGS10N60RUF	Units
V _{CES}	Collector-Emitter Voltage		600	V
V _{GES}	Gate-Emitter Voltage		± 20	V
	Collector Current	@ T _C = 25°C	16	А
I _C	Collector Current	@ T _C = 100°C	10	Α
I _{CM (1)}	Pulsed Collector Current		30	А
	Short Circuit Withstand Time	@ T _C = 100°C	10	μs
T _{SC} P _D	Maximum Power Dissipation	@ T _C = 25°C	55	W
	Maximum Power Dissipation	@ T _C = 100°C	22	W
TJ	Operating Junction Temperature		-55 to +150	°C
T _{stg}	Storage Temperature Range		-55 to +150	°C
T _L	Maximum Lead Temp. for soldering Purposes, 1/8" from case for 5 seconds		300	°C

Notes

(1) Repetitive rating : Pulse width limited by max. junction temperature

Thermal Characteristics

Symbol	Parameter	Тур.	Max.	Units
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case		2.3	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient		62.5	°C/W

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Units
Off Cha	racteristics					
BV _{CES}	Collector-Emitter Breakdown Voltage	$V_{GE} = 0V, I_{C} = 250uA$	600			V
ΔB _{VCES} / ΔΤ _J	Temperature Coeff. of Breakdown Voltage	$V_{GE} = 0V$, $I_C = 1mA$		0.6		V/°C
I _{CES}	Collector Cut-off Current	$V_{CE} = V_{CES}, V_{GE} = 0V$			250	μΑ
I _{GES}	G-E Leakage Current	$V_{GE} = V_{GES}, V_{CE} = 0V$			± 100	nA
On Chai	acteristics					
V _{GE(th)}	G-E Threshold Voltage	$I_C = 10mA$, $V_{CE} = V_{GE}$	5.0	6.0	8.5	V
VGE(th)	Collector to Emitter	$I_C = 10 \text{MA}, V_{GE} = V_{GE}$		2.2	2.8	V
$V_{CE(sat)}$	Saturation Voltage	$I_C = 16A$, $V_{GE} = 15V$		2.5		V
	Catalanon Voltage	10 - 10A, VGE - 15V		2.5		V
Dynami	c Characteristics					
C _{ies}	Input Capacitance	V 20V V 0V		660		pF
C _{oes}	Output Capacitance	$V_{CE} = 30V, V_{GE} = 0V,$ f = 1MHz		115		pF
C _{res}	Reverse Transfer Capacitance			25		pF
t _{d(on)}	Turn-On Delay Time			15		ns
	,					
t _r	Rise Time			30		ns
t _{d(off)}	Turn-Off Delay Time	$V_{CC} = 300 \text{ V}, I_{C} = 10\text{A},$		36	50	nS
t _f	Fall Time	$R_G = 20\Omega$, $V_{GE} = 15V$,		158	200	ns
E _{on}	Turn-On Switching Loss	Inductive Load, T _C = 25°C		141		μJ
E _{off}	Turn-Off Switching Loss			215		μJ
E _{ts}	Total Switching Loss			356	500	μJ
t _{d(on)}	Turn-On Delay Time			16		ns
t _r	Rise Time			33		ns
t _{d(off)}	Turn-Off Delay Time	$V_{CC} = 300 \text{ V}, I_{C} = 10\text{A},$		42	60	ns
t _f	Fall Time	$R_G = 20\Omega$, $V_{GE} = 15V$,		242	350	ns
E _{on}	Turn-On Switching Loss	Inductive Load, T _C = 125°C		161		μJ
E _{off}	Turn-Off Switching Loss			452		μJ
E _{ts}	Total Switching Loss			613	860	μJ
T _{sc}	Short Circuit Withstand Time	V _{CC} = 300 V, V _{GE} = 15V @ T _C = 100°C	10			μs
Q_g	Total Gate Charge	V 200 V I = 404		30	45	nC
Q _{ge}	Gate-Emitter Charge	$V_{CE} = 300 \text{ V, } I_{C} = 10 \text{A,}$ $V_{GE} = 15 \text{V}$		5	10	nC
Q _{gc}	Gate-Collector Charge	v GE - 13 v		8	16	nC
		Measured 5mm from PKG		7.5		nΗ

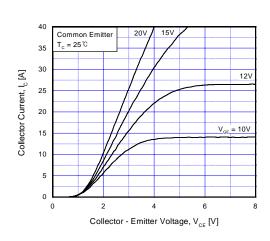


Fig 1. Typical Output Chacracteristics

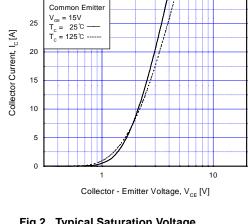


Fig 2. Typical Saturation Voltage Characteristics

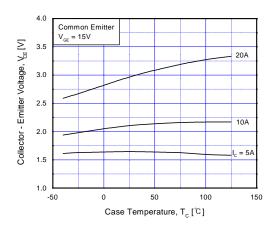


Fig 3. Saturation Voltage vs. Case
Temperature at Variant Current Level

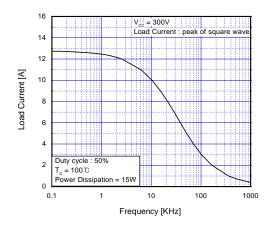


Fig 4. Load Current vs. Frequency

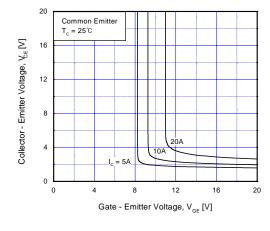


Fig 5. Saturation Voltage vs. V_{GE}

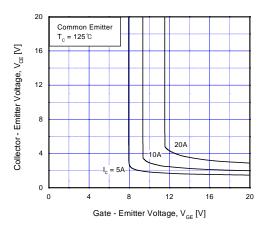
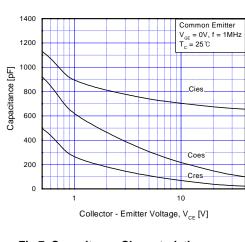


Fig 6. Saturation Voltage vs. V_{GE}

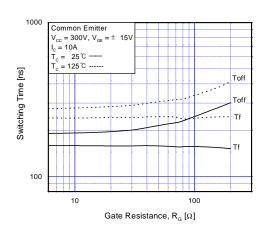
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Common Emitter $V_{cc} = 300V, V_{cg} = \pm 15V$ $I_c = 10A$ $T_c = 25 \text{ C} - \text{T}_c = 125 \text{$

Fig 7. Capacitance Characteristics

Fig 8. Turn-On Characteristics vs.
Gate Resistance



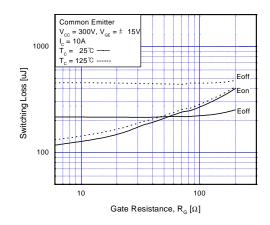
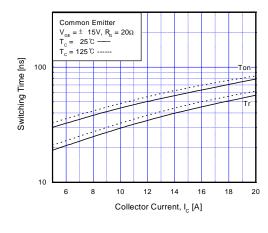


Fig 9. Turn-Off Characteristics vs.
Gate Resistance

Fig 10. Switching Loss vs. Gate Resistance



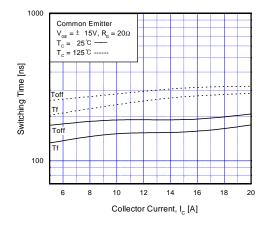
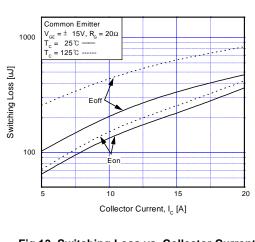


Fig 11. Turn-On Characteristics vs. Collector Current

Fig 12. Turn-Off Characteristics vs. Collector Current

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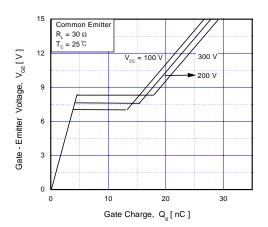
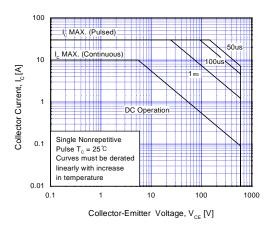


Fig 13. Switching Loss vs. Collector Current

Fig 14. Gate Charge Characteristics



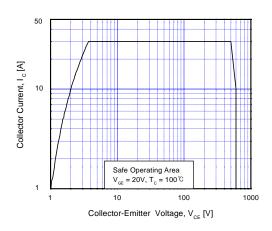


Fig 15. SOA Characteristics

Fig 16. Turn-Off SOA Characteristics

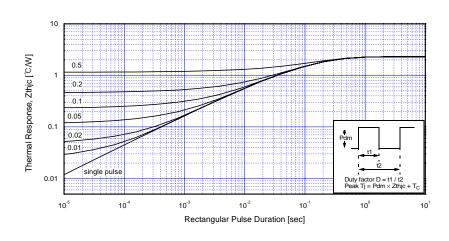
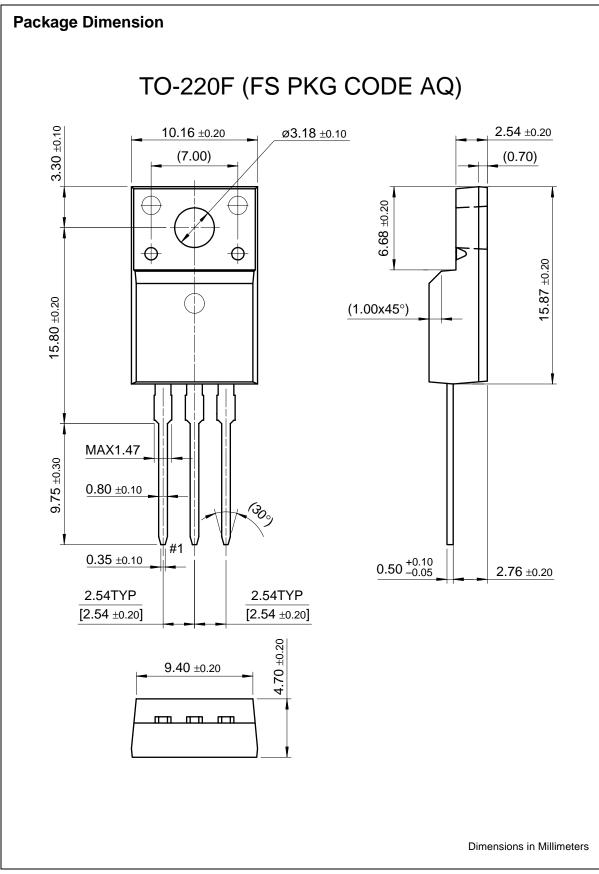


Fig 17. Transient Thermal Impedance of IGBT

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